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Vertical-Cavity Surface-Emitting Lasers XV

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Chun Lei**
Editors

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Contents

vii	<i>Conference Committee</i>
ix	<i>Introduction</i>

SESSION 1 VCSEL FOR OPTICAL INTERCONNECTS

- 7952 04 **1060-nm VCSEL for inter-chip optical interconnection** [7952-03]
K. Takaki, S. Imai, S. Kamiya, H. Shimizu, Y. Kawakita, K. Hiraiwa, T. Takagi, H. Shimizu, J. Yoshida, T. Ishikawa, N. Tsukiji, A. Kasukawa, Furukawa Electric Co., Ltd. (Japan)
- 7952 05 **850-nm oxide high speed VCSEL development at Avago** [7952-04]
J. Wang, C. Ji, D. Soderstrom, T. Jian, L. Giovane, Avago Technologies (United States); S. Ray, Z.-W. Feng, F. Hopfer, J.-K. Hwang, T. Sale, S. J. Taslim, C. Chu, Avago Technologies (Singapore)

SESSION 2 COMMERCIAL VCSEL DEVELOPMENT

- 7952 06 **New high speed VCSEL product development at Emcore (Invited Paper)** [7952-05]
C. Xie, N. Li, C. Lei, X. Sun, W. Luo, L. Zhao, C. Helms, C. Liu, D. Jessen, R. Carson, Emcore Corp. (United States)
- 7952 07 **High power VCSEL systems for tailored intensity distributions** [7952-06]
H. Moench, Philips Research Labs. (Germany); S. Gronenborn, RWTH Aachen (Germany); M. Miller, Philips Technologie GmbH U-L-M Photonics (Germany); P. Loosen, RWTH Aachen (Germany)
- 7952 08 **Record high temperature high output power red VCSELS** [7952-07]
K. Johnson, M. Hibbs-Brenner, W. Hogan, M. Dummer, K. Dogubo, G. Berg, Vixar (United States)

SESSION 3 VCSEL RELIABILITY AND CHARACTERIZATION

- 7952 09 **Phenomenological study of VCSEL wearout reliability** [7952-08]
J. K. Guenter, B. Hawkins, R. A. Hawthorne, Finisar (United States)
- 7952 0B **Spin induced gigahertz polarization oscillations in vertical-cavity surface-emitting laser devices** [7952-10]
M. Y. Li, H. Jaehme, H. Soldat, N. C. Gerhardt, M. R. Hofmann, Ruhr-Univ. Bochum (Germany); T. Ackemann, Univ. of Strathclyde (United Kingdom)
- 7952 0C **Electrical characterization of long wavelength VCSELS with tunnel junction** [7952-11]
A. Consoli, Univ. Politécnic de Madrid (Spain); J. Arias, Univ. Miguel Hernández (Spain); J. M. Tijero, F. J. López Hernández, I. Esquivias, Univ. Politécnic de Madrid (Spain)

SESSION 4 VCSEL SENSORS AND APPLICATIONS

- 7952 0D **Single mode and tunable GaSb-based VCSELs for wavelengths above 2 μm (Invited Paper)** [7952-12]
M.-C. Amann, S. Arafın, K. Vizbaras, Technische Univ. München (Germany)
- 7952 0E **Modeling of compact Pd coated VCSELs for hydrogen sensing** [7952-13]
C. Edwards, L. L. Goddard, Univ. of Illinois at Urbana-Champaign (United States)
- 7952 0F **A VCSEL based system for on-site monitoring of low level methane emission** [7952-14]
A. Kannath, Cranfield Univ. (United Kingdom) and Geotechnical Instruments Ltd. (United Kingdom); J. Hodgkinson, Cranfield Univ. (United Kingdom); R. G. Gillard, R. J. Riley, Geotechnical Instruments Ltd. (United Kingdom); R. P. Tatam, Cranfield Univ. (United Kingdom)
- 7952 0G **Efficient vertical-cavity surface-emitting lasers for infrared illumination applications** [7952-15]
J.-F. Seurin, G. Xu, B. Guo, A. Miglo, Q. Wang, P. Pradhan, J. D. Wynn, V. Khalfin, W.-X. Zou, C. Ghosh, R. Van Leeuwen, Princeton Optronics (United States)

SESSION 5 HIGH SPEED VCSELS

- 7952 0H **High-speed highly temperature stable 980-nm VCSELs operating at 25 Gb/s at up to 85 °C for short reach optical interconnects (Invited Paper)** [7952-16]
A. Mutig, Technische Univ. Berlin (Germany); J. A. Lott, VI Systems GmbH (Germany); S. A. Blokhin, Technische Univ. Berlin (Germany) and Saint Petersburg Physical-Technological Ctr. for Research and Education (Russian Federation); P. Moser, P. Wolf, W. Hofmann, Technische Univ. Berlin (Germany); A. M. Nadtochiy, Technische Univ. Berlin (Germany) and Saint Petersburg Physical-Technological Ctr. for Research and Education (Russian Federation); D. Bimberg, Technische Univ. Berlin (Germany)
- 7952 0J **High-speed single-mode quantum dot and quantum well VCSELs** [7952-18]
N. N. Ledentsov, J. A. Lott, VI Systems GmbH (Germany); D. Bimberg, A. Mutig, G. Fiol, Technische Univ. Berlin (Germany); S. A. Blokhin, Connector Optics LLC (Russian Federation); A. M. Nadtochiy, Saint Petersburg Physical-Technological Ctr. for Research and Education (Russian Federation) and A. F. Ioffe Physical Technical Institute (Russian Federation); V. A. Shchukin, J.-R. Kropp, VI Systems GmbH (Germany); I. I. Novikov, L. Ya. Karachinsky, Connector Optics LLC (Russian Federation); M. V. Maximov, A. F. Ioffe Physical Technical Institute (Russian Federation)
- 7952 0K **Higher speed VCSELs by photon lifetime reduction** [7952-19]
P. Westbergh, J. S. Gustavsson, B. Kögel, Å. Haglund, A. Larsson, Chalmers Univ. of Technology (Sweden); A. Joel, IQE Europe Ltd. (United Kingdom)

SESSION 6 INNOVATIVE VCSEL STRUCTURES

- 7952 0L **Fully micro-fabricated VECSEL at 850 nm (Invited Paper)** [7952-20]
D. K. Serkland, K. M. Geib, G. A. Keeler, G. M. Peake, Sandia National Labs. (United States)

- 7952 0M **Feedback in close-coupled axial VCSEL-photodiode pairs** [7952-21]
K. M. Geib, D. K. Serkland, G. M. Peake, Sandia National Labs. (United States); V. M. Sanchez, LMATA Government Services (United States)
- 7952 0N **Transverse mode selection and injection locking in 1550-nm multimode VCSELs induced by optical injection** [7952-22]
A. Quirce, A. Valle, L. Pesquera, Univ. de Cantabria (Spain); A. Hurtado, M. J. Adams, Univ. of Essex (United Kingdom)
- 7952 0O **Scaling properties of lithographic VCSELs** [7952-23]
A. Demir, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States) and sdPhotonics LLC (United States); G. Zhao, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States); S. Freisem, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States) and sdPhotonics LLC (United States); X. Liu, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States); D. G. Deppe, CREOL, The College of Optics and Photonics, Univ. of Central Florida (United States) and sdPhotonics LLC (United States)

Author Index

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- 1 VCSEL for Optical Interconnects
Chun Lei, Emcore Corporation (United States)
- 2 Commercial VCSEL Development
James A. Lott, VI Systems GmbH (Germany) and Technische Universität Berlin (Germany)

- 3 VCSEL Reliability and Characterization
Martin Grabherr, Philips Technologie GmbH U-L-M Photonics
(Germany)
- 4 VCSEL Sensors and Applications
Kent M. Geib, Sandia National Laboratories (United States)
- 5 High Speed VCSELS
James K. Guenter, Finisar Corporation (United States)
- 6 Innovative VCSEL Structures
Kent D. Choquette, University of Illinois at Urbana-Champaign (United
States)

Introduction

On 26 and 27 January 2011 the Vertical Cavity Surface Emitting Lasers XV conference saw its second year in San Francisco as part of the SPIE Photonics West symposium. After a decade and a half of dedicated conferences, it is clear that VCSEL technology is well-developed, so much so that this year for the first time, a completely separate conference was held for Vertical External Cavity Surface Emitting Lasers (VECSELs), which share many structural details with VCSELs, and which in previous years, might have been included in the VCSEL conference. In addition, dozens of papers in other conferences either used or modified VCSELs for specific applications in biomedicine, communications, and sensing.

In the VCSEL conference itself, we saw some of the wide variety of applications that VCSELs are filling today, with papers on VCSEL wavelengths from the visible red out to nearly 3 μm in the infrared. Applications ranged from the very high power, as much as kW, for illumination and pumping, to extremely low power—and therefore “green”—short-range communications. Several papers vied for the highest-speed modulation of VCSELs, with rates as high as 40 Gbps demonstrated. New approaches to fabricating VCSELs and even monolithic VECSELs were presented. Some unusual VCSEL physics was presented, and even a few mysteries on the reliability and testing front. Finally, some specific sensing applications using modified VCSEL chips to enable extreme miniaturization were presented.

This proceedings volume contains the manuscripts of papers presented during the conference, papers that document the continuing advancement of VCSEL optoelectronic technology, and pave the way for VCSEL XVI next year.

**James K. Guenter
Chun Lei**

